

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-330001	Application No. 10/616,504
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Henry A. Hill	
		Filing Date July 8, 2003	Group Art Unit 2877

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
PJC	AA	4,413,908	11/1983	Abrams et al.			
	AB	4,948,254	08/1990	Ishida			
	AC	5,151,749	09/29/1992	Tanimoto et al.			
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Examiner Signature PATRICK CONNOLLY	Date Considered 03.31.2005
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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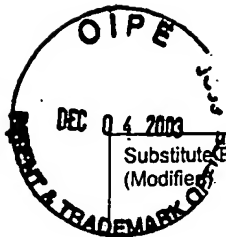
Foreign Patent Documents or Published Foreign Patent Applications

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							Yes	No
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Examiner Initial	Desig. ID	Document
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PJC	ALL	Bennett, S.J. <u>Optics Communications</u> , 4:6, pp. 428-430, 1972
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PJC	APP	Wu, C.M. et al., "Analytical Modeling of the Periodic Nonlinearity in Heterodyne Interferometry," APPLIED OPTICS, Vol. 37, No. 28, 1 October 1998, pp. 6696-6700.
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(37 CFR §1.98(b))

Applicant
Henry A. HillFiling Date
July 8, 2003Group Art Unit
2877**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AD						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclasses	Translation	
							Yes	No
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PJC	AF	0 689 030 A2	12/27/1995	EPO	G01B	9/02		
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Examiner Initial	Desig. ID	Document
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PJC	AK	Mitsuru Tanaka, et al., "Linear Interpolation of Periodic Error in a Heterodyne Laser Interferometer at Subnanometer Levels", <u>IEEE Transactions on Instrumentation and Measurement</u> , Vol. 38, No. 2, pp. pp. 553-554 (April 1989)
PJC	AL	Chien-Ming Wu et al., "Analytical modeling of the periodic nonlinearity in heterodyne interferometry", <u>Applied Optics</u> , Vol. 37, No. 28, pp. 6696-6700 (October 1, 1998)
PJC	AM	Chien-Ming Wu et al., "Nonlinearity in measurements of length by optical interferometry", <u>Measurement Science and Technology</u> , Vol. 7, No. 1, pp. 62-68 (January 1996)
	AN	
	AO	

Examiner Signature

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